Session 3B: Memory Testing
Moderators: F. Corsi, Politecnico di Bari, Italy, and M. Nicolaidis, TIMA/INPG, France

The first two papers present new algorithms for testing word-oriented DRAMs and shifting-type FIFOs respectively. The last paper deals with a practical implementation of a very high speed BISTed SRAMs and CAMs.

Pseudo-Exhaustive Word-Oriented DRAM Testing
M.G. Karpovsky, V.N. Yarmolik, and A.J. van de Goor

Functional Test for Shifting-Type FIFOs
A.J. van de Goor, I. Schanstra, and Y. Zorian

A 370-Mhz Memory Built-in Self-Test State Machine